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ISO/TS16949:2002
FILE NO. A9273

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Reliability Test Summary

RTS No: 1173

Device Family: IC Lighting Product**Packages:** DFN1443, MSOP8, MSOP10, QFN1644, SC70-6, SO8, SOT23, SOT23-5, SOT23-6, TSOT23-5**Date From:** 27/06/2007**Date To:** 24/07/2008**Environmental Trial Data**

Trial Type	Specification	Lots	Devices Tested	Devices Failed	Cumulative Hours	% Failures
CS (Cold Store)	JESD22-A119	1	45	0	45360	0.000
HS (Hot Store)	JESD22-A103	2	90	0	90720	0.000
PCLV (Pre-conditioned Autoclave)	JESD22-A102	2	154	0	14784	0.000
PTC (Pre-conditioned Temperature Cycle Air to Air)	JESD22-A104	2	154	0	155232	0.000
PTHB (Pre-conditioned Temperature Humidity + Bias)	JESD22-A101	2	154	0	155232	0.000
RSHF (Resistance to Solder Heat Float)	JESD22-B106	1	45	0	45	0.000
Solderability (Post Hot Store)	IEC68-2-20	4	180	0	855	0.000

Electrical Stress TrialsElectrical Trial Type: **HTOL (High Temperature Operating Life - JESD22-A108)**

Service Temperature (Deg C): 55

Ambient Temperature (Deg C): 125

Activation Energy (eV): 0.9

Confidence Level (%): 60

Actual Device Hours 314379.4286

Equivalent Device Hours 8.489E+07

Lots 7

Devices Tested: 361

Devices Failed: 0

Mean Time To Failure (Hours): 9.265E+07

Failure Rate FITs: 10.7934

Failure Rate %/1000 Hours: 1.079E-03

David Fitton
Quality Engineer